

Date: February 4, 2004 Page 1 of 2

FORM PTO-1449	ATTY DOCKET NO. COLB-124XX	SERIAL NUMBER 10/673,996
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT Tzachi RAFAELI, et al.	EXAMINER
	FILING DATE September 29, 2003	GROUP ART UNIT 2882

U.S. PATENT DOCUMENTS

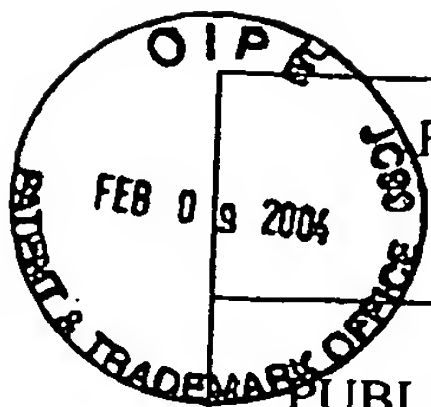
Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
<i>JRA</i>	AA	3,256,431	6/14/1966	Fraser	250	43.5	
	AB	3,581,087	5/25/1971	Brinkerhoff	250	51.5	
	AC	3,980,568	9/14/1976	Pitchford, et al.	250	276	
	AD	4,852,135	7/25/1989	Anisovich, et al.	378	49	
	AE	5,497,008	3/5/1996	Kumakhov	250	505.1	
	AF	5,778,039	7/7/1998	Hossain, et al.	378	45	
	AG	5,937,026	8/10/1999	Satoh	378	44	
	AH	5,812,631	9/22/1998	Yan, et al.	378	85	
<i>J</i>	AI	6,108,398	8/22/2000	Mazor, et al.	378	45	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANS- LATION
<i>JRA</i>	AJ	DE 19705732A1	10/30/1997	Germany (with English Abstract)			No

OTHER ART (Including Author, Bills, Pertinent Pages, Etc.)

<i>JRA</i>	AK	Brochure: Capillary Optics, by X-Ray Capillary Optics AB, Sweden 1995.
	AL	N. Yamamoto, "A Micro-Fluorescent/Diffracted X-Ray Spectrometer With A Micro-X-Ray Beam Formed By A Fine Glass Capillary", Rev. Sci. Instrum. 67(9), September 1996, pp. 3051,3054-3056,3062.
<i>J</i>	AM	B.J. Cross, et al., "X-Ray Microfluorescence Analyzer For Multilayer Metal Films", Thin Solid 166 (1988), pp. 263-272.
EXAMINER:	<i>JRA</i>	DATE CONSIDERED: 12/15/04
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		



Date: February 4, 2004 Page 2 of 2

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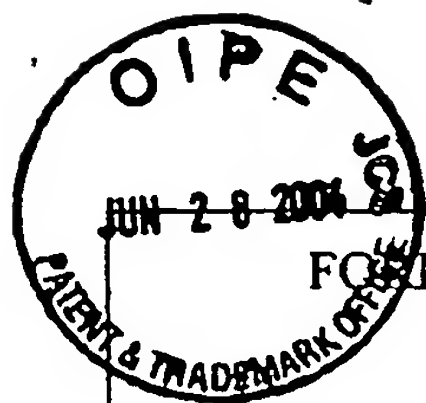
Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANS- LATION
	AI						
	AJ						

OTHER ART (Including Author, Bills, Pertinent Pages, Etc.)

<i>JRA</i>	AK	Shimomura, et al., "Annular-Type Solid State Detector For A Scanning X-Ray Analytical Microscope", Rev. Sci. Instrum. 66(9) (September 1995), pp. 4544-4546.
<i>JRA</i>	AL	Longoni et al., "A New XRF Spectrometer Based on a Ring-Shaped Multi-Element Silicon Drift Detector and on X-Ray Capillary Optics", IEEE Transactions on Nuclear Science 49:3 (2002), pages 1001-1005.
	AM	
EXAMINER:	<i>JRA</i>	DATE CONSIDERED: 12/15/04
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Date: June 24, 2004 Page 1 of 1

FORM PTO-1449 (Colb)	ATTY DOCKET NO. COLB-124XX	SERIAL NUMBER 10/673,996
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT Tzachi RAFAELI, et al.	EXAMINER (N/A)
	FILING DATE September 29, 2003	GROUP ART UNIT 2882

U.S. PATENT DOCUMENTS

Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
<i>RA</i>	AA	6,744,950	06-2004	Aleksoff			
	AB	6,643,354	11-2003	Koppel, et al.			
	AC	6,507,634	01-2003	Koppel, et al.			
	AD	6,453,006	09-2002	Koppel, et al.			
	AE	2004/0052330	03-2004	Koppel, et al.			
	AF	2002/0110218	08-2002	Koppel, et al.			
	AG	2002/0097837	07-2002	Fanton, et al.			
	AH	6,711,232	03-2004	Janik			
<i>AK</i>	AI	5,619,548	Apr. 1997	Koppel			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANS- LATION
	AJ						

OTHER ART (Including Author, Bills, Pertinent Pages, Etc.)

	AK	
	AL	
	AM	
EXAMINER:	<i>[Signature]</i>	DATE CONSIDERED: 12/15/04
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